

November 2013

FQP20N06

N-Channel QFET[®] MOSFET 60 V, 20 A, 60 m Ω

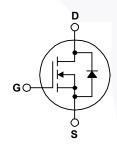
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- 20 A, 60 V, $R_{DS(on)}$ = 60 m Ω (Max.) @ V_{GS} = 10 V, I_D = 10 A
- Low Gate Charge (Typ. 11.5 nC)
- · Low Crss (Typ. 25 pF)
- · 100% Avalanche Tested
- · 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQP20N06	Unit
V_{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°C)	20	Α
	- Continuous (T _C = 100°	C)	14.1	А
I _{DM}	Drain Current - Pulsed	(Note 1)	80	Α
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	155	mJ
I _{AR}	Avalanche Current	(Note 1)	20	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P _D	Power Dissipation (T _C = 25°C)		53	W
- Derate above 25°C		0.35	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Rang	е	-55 to +175	°C
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQP20N06	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.85	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQP20N06	FQP20N06	TO-220	Tube	N/A	N/A	50 units

Electrical	Characteristics	
Fiectrical	Characteristics	T

$T_C =$	25°C	unless	otherwise	noted.

Parameter	Test Conditions	Min	Тур	Max	Unit
racteristics					
Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.07		V/°C
Zara Cata Valtaga Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
Zero Gate Voltage Drain Current	V _{DS} = 48 V, T _C = 150°C			10	μΑ
Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V	-		100	nA
Gate-Body Leakage Current, Reverse	V _{GS} = -25 V, V _{DS} = 0 V			-100	nA
	Drain-Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward	tracteristics Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced to 25°C Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$ $V_{DS} = 48 \text{ V}$, $V_{CS} = 150 \text{ °C}$ Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		0.048	0.06	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_{D} = 10 \text{ A}$		12		S

Dynamic Characteristics

C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$	 450	590	pF
C _{oss}	Output Capacitance	f = 1.0 MHz	 170	220	pF
C _{rss}	Reverse Transfer Capacitance		 25	35	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	V _{DD} = 30 V, I _D = 10 A,		5	20	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		45	100	ns
t _{d(off)}	Turn-Off Delay Time			20	50	ns
t _f	Turn-Off Fall Time	(Note 4)	/	25	60	ns
Q_g	Total Gate Charge	V _{DS} = 48 V, I _D = 20 A,		11.5	15	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V	A	3		nC
Q_{gd}	Gate-Drain Charge	(Note 4)		4.5	/	nC

Drain-Source Diode Characteristics and Maximum Ratings

I _S	Maximum Continuous Drain-Source Diode Forward Current				20	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				80	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 20 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 20 A,		43		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs		50		nC

- Notes: Notes: Notes: A Repetitive Rating: Pulse width limited by maximum junction temperature.
 2. L = 450 μ H, I_{AS} = 20 A, V_{DD} = 25 V, R_G = 25 Ω , starting T_J = 25°C.
 3. I_{SD} \leq 20 A, di/dt \leq 300 A/ μ s, V_{DD} \leq BV_{DSS}, starting T_J = 25°C.
 4. Essentially Independent of Operating Temperature.

Typical Characteristics

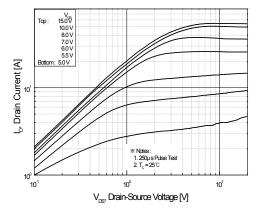


Figure 1. On-Region Characteristics

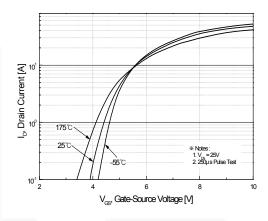


Figure 2. Transfer Characteristics

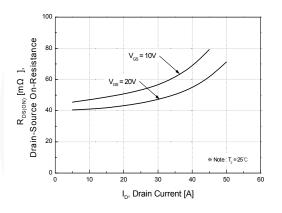


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

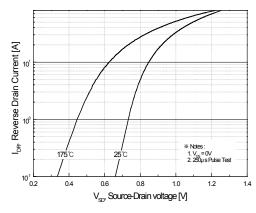


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

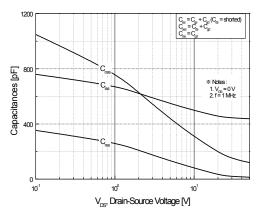


Figure 5. Capacitance Characteristics

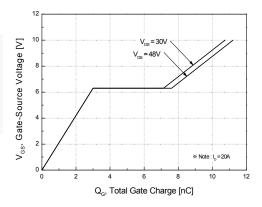


Figure 6. Gate Charge Characteristics

Typical Characteristics (continued)

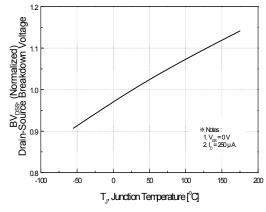


Figure 7. Breakdown Voltage Variation vs. Temperature

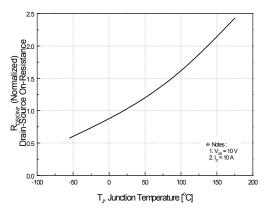


Figure 8. On-Resistance Variation vs. Temperature

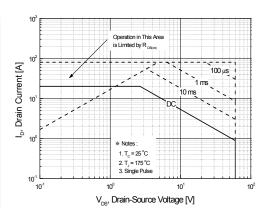


Figure 9. Maximum Safe Operating Area

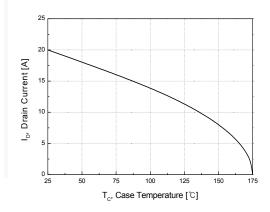


Figure 10. Maximum Drain Current v.s Case Temperature

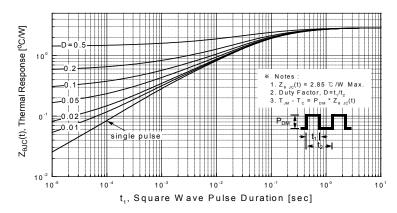


Figure 11. Transient Thermal Response Curve

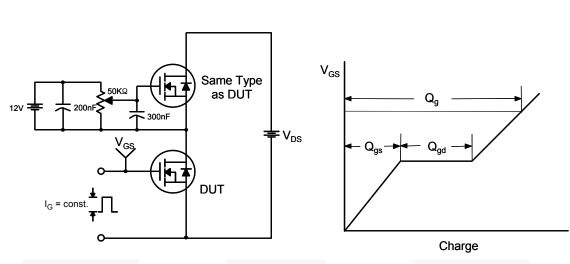


Figure 12. Gate Charge Test Circuit & Waveform

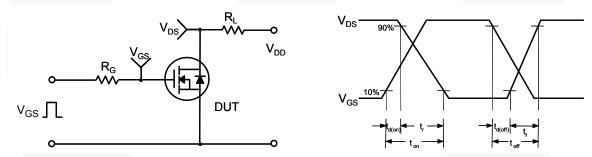


Figure 13. Resistive Switching Test Circuit & Waveforms

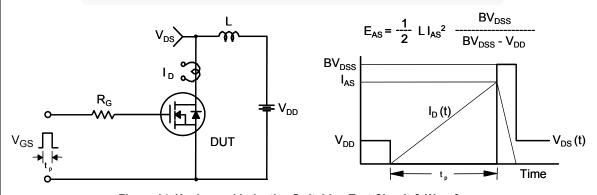
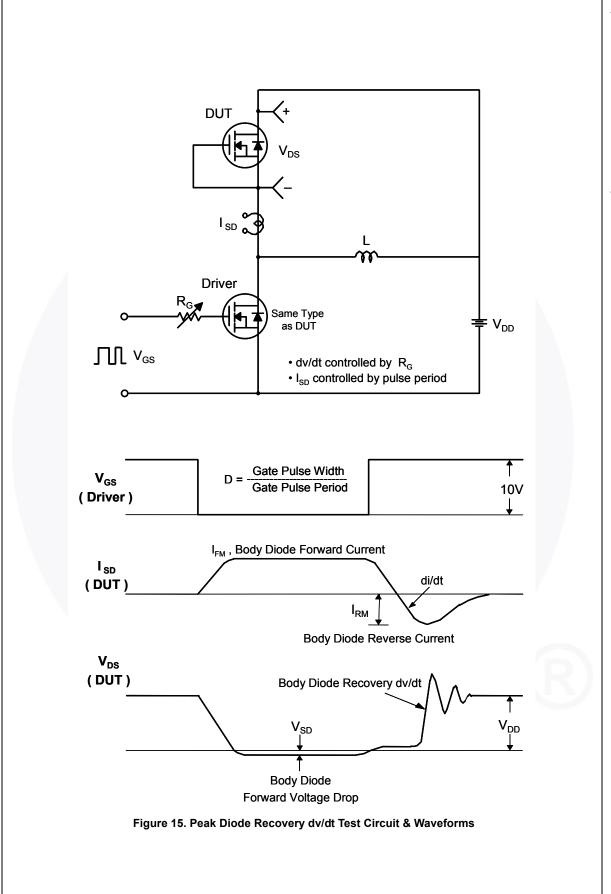
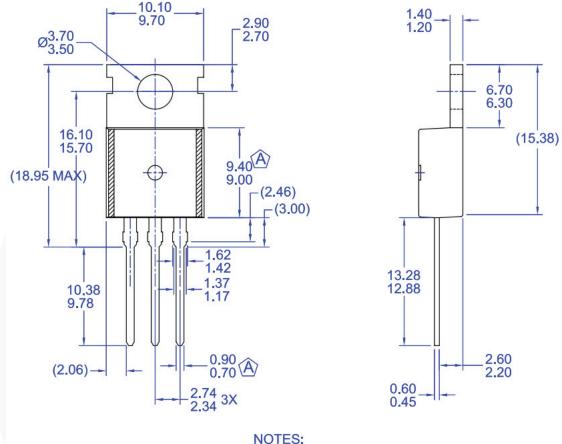


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



Mechanical Dimensions



(A) CONFORMS TO JEDEC TO-220

4.70 4.30

9.80

- VARIATION AB EXCEPT WHERE NOTED B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D) DRAWING FILE/REVISION: MKT-TO220Y03REV1

Figure 16. TO220, Molded, 3-Lead, Jedec Variation AB

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